# Supporting Information - Rigidity of Lamellar Nanosheets

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| $n$ | *'10 nm'* | *'20 nm'* | *'40 nm'* |
|---|---|---|---|
| *1* | (14.6 ± 0.6) nm | (20.5 ± 1.0) nm | (40.3 ± 2.0) nm |
| *2* | (10 ± 0.5) nm | (20.6 ± 0.8) nm | (42.3 ± 1.0) nm |
| *3* | (11 ± 0.6) nm | (18.4 ± 1.0) nm | (40 ± 2.0) nm |
| *4* | (10.4 ± 0.5) nm | (18.7 ± 0.8) nm | (41.6 ± 1.0) nm |
| *5* | (14.4 ± 0.6) nm | (19.8 ± 1.0) nm | (41.3 ± 2.0) nm |
| *6* | (11 ± 0.5) nm | (21.5 ± 0.8) nm | (40.8 ± 1.0) nm |

**Table S1**: The measured film thickness and the associated experimental uncertainty for each individual layer. Odd numbered layers are SWCNT ($n$ = 1, 3, 5) and even numbered layers are PS ($n$ = 2, 4, 6).

**Video S1**: Video of a freestanding SWCNT film (78 nm thickness) being handled with a pipette in a solvent of ethanol.